

Search Notes

Application/Control No.

10/022,284

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under
Reexamination

TOMIHARA ET AL.

Art Unit

1745

SEARCHED

Class	Subclass	Date	Examiner
429	137	1/25/2007	DWY
429	206	1/25/2007	DWY
429	209	1/25/2007	DWY
429	212	1/25/2007	DWY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
429	137	1/25/2007	DWY
429	206	1/25/2007	DWY
429	209	1/25/2007	DWY

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	1/25/2007	DWY
Inventorship Search	1/25/2007	DWY